
HM628512C Series

4 M SRAM (512-kword \times 8-bit)

HITACHI

ADE-203-1212B (Z)

Rev. 2.0

May. 14, 2001

Description

The Hitachi HM628512C is a 4-Mbit static RAM organized 512-kword \times 8-bit. It realizes higher density, higher performance and low power consumption by employing CMOS process technology (6-transistor memory cell). The device, packaged in a 525-mil SOP (foot print pitch width) or 400-mil TSOP TYPE II or 600-mil plastic DIP, is available for high density mounting. The HM628512C is suitable for battery backup system.

Features

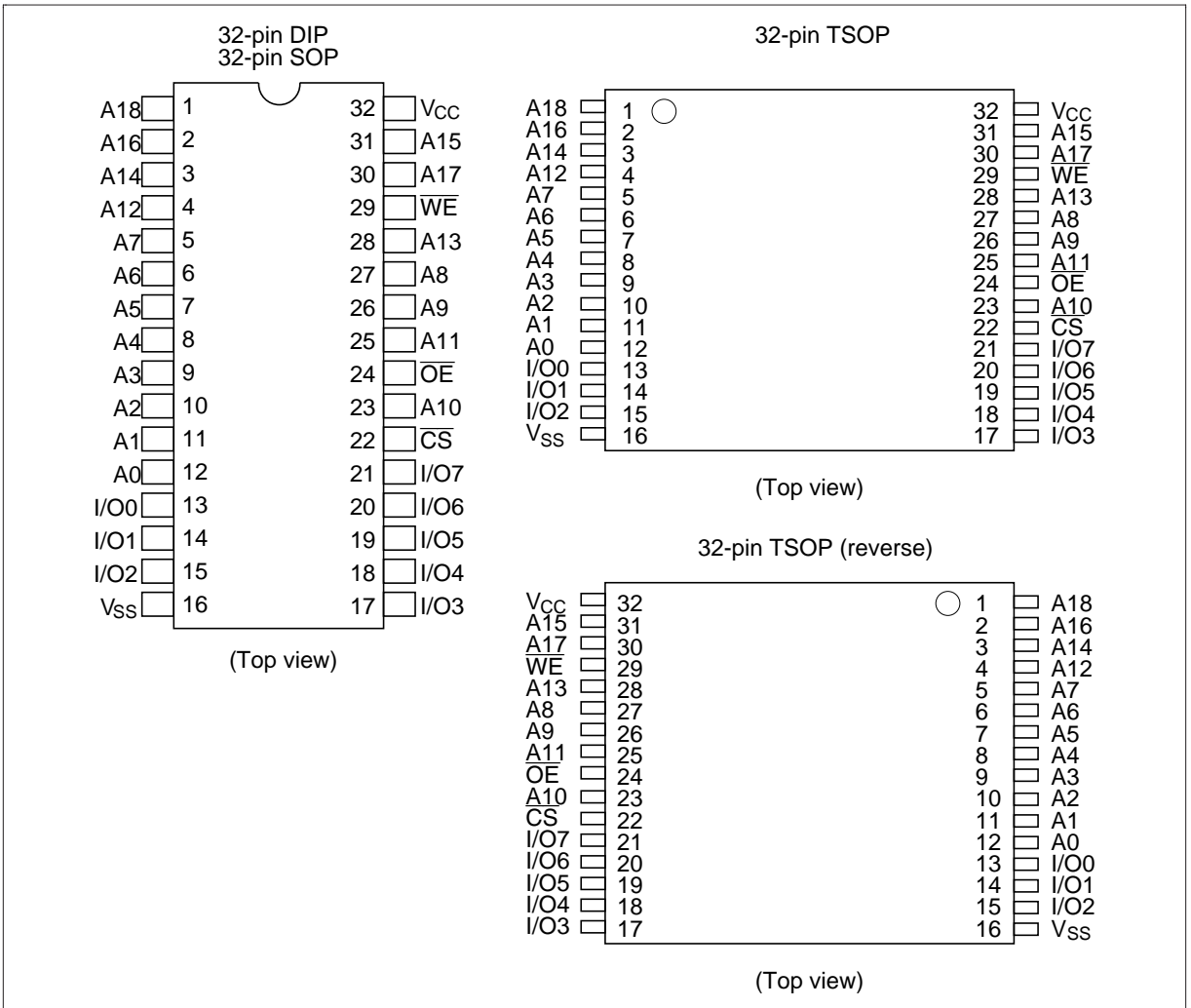
- Single 5 V supply
- Access time: 55/70 ns (max)
- Power dissipation
 - Active: 10 mW/MHz (typ)
 - Standby: 4 μ W (typ)
- Completely static memory. No clock or timing strobe required
- Equal access and cycle times
- Common data input and output: Three state output
- Directly TTL compatible: All inputs and outputs
- Battery backup operation

HM628512C Series

Ordering Information

Type No.	Access time	Package
HM628512CLP-5	55 ns	600-mil 32-pin plastic DIP (DP-32)
HM628512CLP-7	70 ns	
HM628512CLP-5SL	55 ns	
HM628512CLFP-5	55 ns	525-mil 32-pin plastic SOP (FP-32D)
HM628512CLFP-7	70 ns	
HM628512CLFP-5SL	55 ns	
HM628512CLTT-5	55 ns	400-mil 32-pin plastic TSOP II (TTP-32D)
HM628512CLTT-7	70 ns	
HM628512CLTT-5SL	55 ns	
HM628512CLRR-5	55 ns	400-mil 32-pin plastic TSOP II reverse (TTP-32DR)
HM628512CLRR-7	70 ns	
HM628512CLRR-5SL	55 ns	

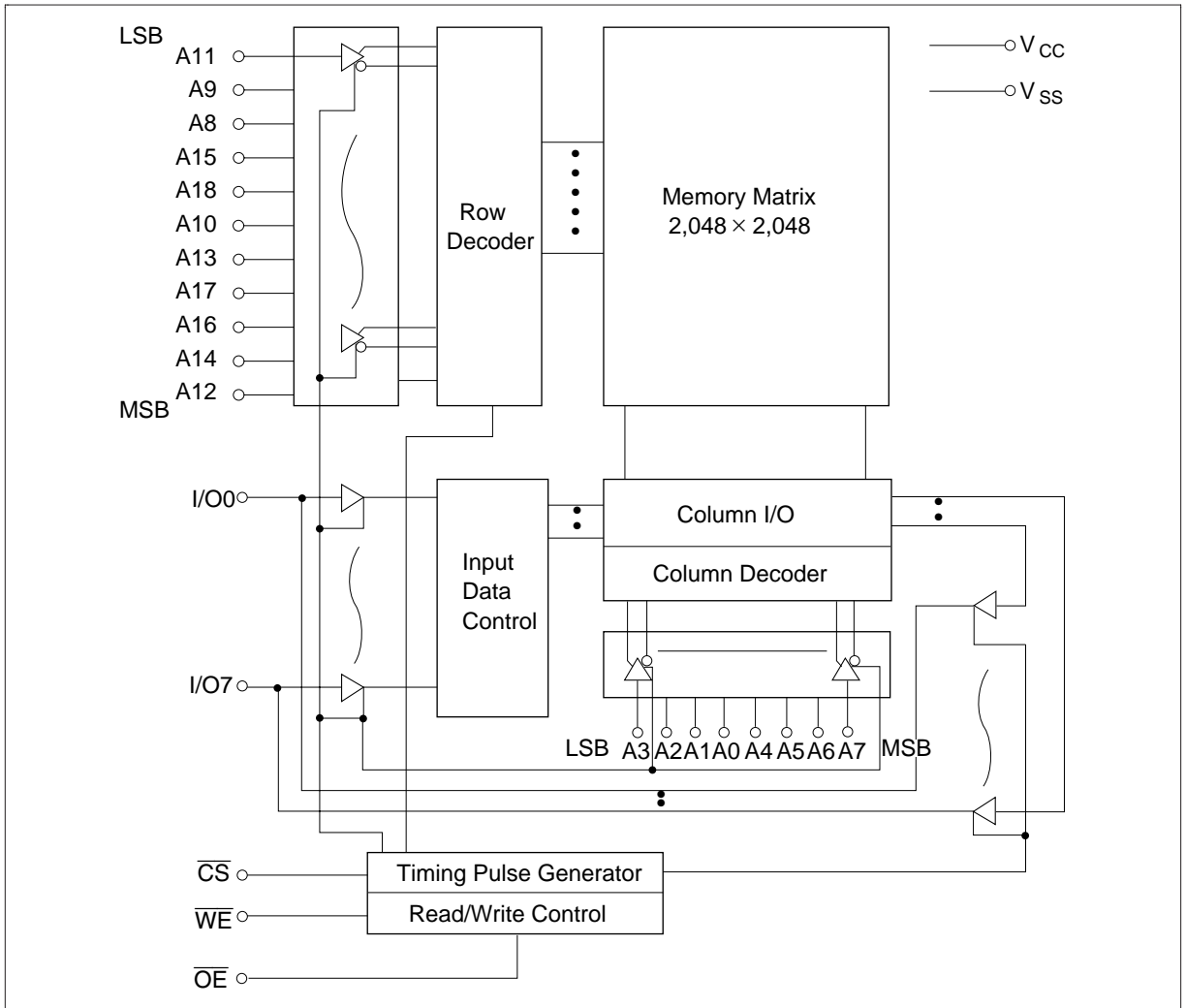
Pin Arrangement



Pin Description

Pin name	Function
A0 to A18	Address input
I/O0 to I/O7	Data input/output
CS	Chip select
OE	Output enable
WE	Write enable
V _{CC}	Power supply
V _{SS}	Ground

Block Diagram



Function Table

\overline{WE}	\overline{CS}	\overline{OE}	Mode	V_{CC} current	Dout pin	Ref. cycle
×	H	×	Not selected	I_{SB}, I_{SB1}	High-Z	—
H	L	H	Output disable	I_{CC}	High-Z	—
H	L	L	Read	I_{CC}	Dout	Read cycle
L	L	H	Write	I_{CC}	Din	Write cycle (1)
L	L	L	Write	I_{CC}	Din	Write cycle (2)

Note: ×: H or L

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Power supply voltage	V_{CC}	-0.5 to +7.0	V
Voltage on any pin relative to V_{SS}	V_T	-0.5* ¹ to $V_{CC} + 0.3$ * ²	V
Power dissipation	P_T	1.0	W
Operating temperature	T_{opr}	-20 to +70	°C
Storage temperature	T_{stg}	-55 to +125	°C
Storage temperature under bias	T_{bias}	-20 to +85	°C

Notes: 1. V_T min: -3.0 V for pulse half-width ≤ 30 ns.

2. Maximum voltage is 7.0 V.

Recommended DC Operating Conditions ($T_a = -20$ to $+70^\circ\text{C}$)

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	V_{CC}	4.5	5.0	5.5	V
	V_{SS}	0	0	0	V
Input high voltage	V_{IH}	2.2	—	$V_{CC} + 0.3$	V
Input low voltage	V_{IL}	-0.3* ¹	—	0.8	V

Note: 1. V_{IL} min: -3.0 V for pulse half-width ≤ 30 ns.

DC Characteristics

Parameter	Symbol	Min	Typ* ¹	Max	Unit	Test conditions
Input leakage current	$ I_{LI} $	—	—	1	μA	$V_{in} = V_{SS}$ to V_{CC}
Output leakage current	$ I_{LO} $	—	—	1	μA	$\overline{CS} = V_{IH}$ or $\overline{OE} = V_{IH}$ or $\overline{WE} = V_{IL}$, $V_{I/O} = V_{SS}$ to V_{CC}
Operating power supply current: DC	I_{CC}	—	1.5	3	mA	$\overline{CS} = V_{IL}$, others = V_{IH}/V_{IL} , $I_{I/O} = 0$ mA
Operating power supply current	HM628512C-5 I_{CC1}	—	8	25	mA	Min cycle, duty = 100% $\overline{CS} = V_{IL}$, others = V_{IH}/V_{IL} $I_{I/O} = 0$ mA
	HM628512C-7 I_{CC1}	—	7	25	mA	
Operating power supply current	I_{CC2}	—	2	5	mA	Cycle time = 1 μs , duty = 100% $I_{I/O} = 0$ mA, $\overline{CS} \leq 0.2$ V $V_{IH} \geq V_{CC} - 0.2$ V, $V_{IL} \leq 0.2$ V
Standby power supply current: DC	I_{SB}	—	0.1	0.5	mA	$\overline{CS} = V_{IH}$
Standby power supply current (1): DC	I_{SB1}	—	0.8^{*2}	20^{*2}	μA	$V_{in} \geq 0$ V, $\overline{CS} \geq V_{CC} - 0.2$ V
		—	0.8^{*3}	10^{*3}	μA	
Output low voltage	V_{OL}	—	—	0.4	V	$I_{OL} = 2.1$ mA
Output high voltage	V_{OH}	2.4	—	—	V	$I_{OH} = -1.0$ mA

Notes: 1. Typical values are at $V_{CC} = 5.0$ V, $T_a = +25^\circ\text{C}$ and specified loading, and not guaranteed.

2. This characteristics is guaranteed only for L version.

3. This characteristics is guaranteed only for L-SL version.

Capacitance ($T_a = +25^\circ\text{C}$, $f = 1$ MHz)

Parameter	Symbol	Typ	Max	Unit	Test conditions
Input capacitance* ¹	C_{in}	—	8	pF	$V_{in} = 0$ V
Input/output capacitance* ¹	$C_{I/O}$	—	10^{*2}	pF	$V_{I/O} = 0$ V

Notes: 1. This parameter is sampled and not 100% tested.

2. $C_{I/O}$ max = 12 pF only for HM628512CLP Series.

AC Characteristics ($T_a = -20$ to $+70^\circ\text{C}$, $V_{CC} = 5\text{ V} \pm 10\%$, unless otherwise noted.)

Test Conditions

- Input pulse levels: 0.8 V to 2.4 V
- Input rise and fall time: 5 ns
- Input and output timing reference levels: 1.5 V
- Output load: 1 TTL Gate + C_L (100 pF) (HM628512C-7)
 1 TTL Gate + C_L (50 pF) (HM628512C-5)
 (Including scope & jig)

Read Cycle

Parameter	Symbol	HM628512C				Unit	Notes
		-5		-7			
		Min	Max	Min	Max		
Read cycle time	t_{RC}	55	—	70	—	ns	
Address access time	t_{AA}	—	55	—	70	ns	
Chip select access time	t_{CO}	—	55	—	70	ns	
Output enable to output valid	t_{OE}	—	25	—	35	ns	
Chip selection to output in low-Z	t_{LZ}	10	—	10	—	ns	2
Output enable to output in low-Z	t_{OLZ}	5	—	5	—	ns	2
Chip deselection to output in high-Z	t_{HZ}	0	20	0	25	ns	1, 2
Output disable to output in high-Z	t_{OHZ}	0	20	0	25	ns	1, 2
Output hold from address change	t_{OH}	10	—	10	—	ns	

Write Cycle

Parameter	Symbol	HM628512C				Unit	Notes
		-5		-7			
		Min	Max	Min	Max		
Write cycle time	t_{WC}	55	—	70	—	ns	
Chip selection to end of write	t_{CW}	50	—	60	—	ns	4
Address setup time	t_{AS}	0	—	0	—	ns	5
Address valid to end of write	t_{AW}	50	—	60	—	ns	
Write pulse width	t_{WP}	40	—	50	—	ns	3, 12
Write recovery time	t_{WR}	0	—	0	—	ns	6
\overline{WE} to output in high-Z	t_{WHZ}	0	20	0	25	ns	1, 2, 7
Data to write time overlap	t_{DW}	25	—	30	—	ns	
Data hold from write time	t_{DH}	0	—	0	—	ns	
Output active from output in high-Z	t_{OW}	5	—	5	—	ns	2
Output disable to output in high-Z	t_{OHZ}	0	20	0	25	ns	1, 2, 7

Notes: 1. t_{HZ} , t_{OHZ} and t_{WHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

2. This parameter is sampled and not 100% tested.

3. A write occurs during the overlap (t_{WP}) of a low \overline{CS} and a low \overline{WE} . A write begins at the later transition of \overline{CS} going low or \overline{WE} going low. A write ends at the earlier transition of \overline{CS} going high or \overline{WE} going high. t_{WP} is measured from the beginning of write to the end of write.

4. t_{CW} is measured from \overline{CS} going low to the end of write.

5. t_{AS} is measured from the address valid to the beginning of write.

6. t_{WR} is measured from the earlier of \overline{WE} or \overline{CS} going high to the end of write cycle.

7. During this period, I/O pins are in the output state so that the input signals of the opposite phase to the outputs must not be applied.

8. If the \overline{CS} low transition occurs simultaneously with the \overline{WE} low transition or after the \overline{WE} transition, the output remain in a high impedance state.

9. Dout is the same phase of the write data of this write cycle.

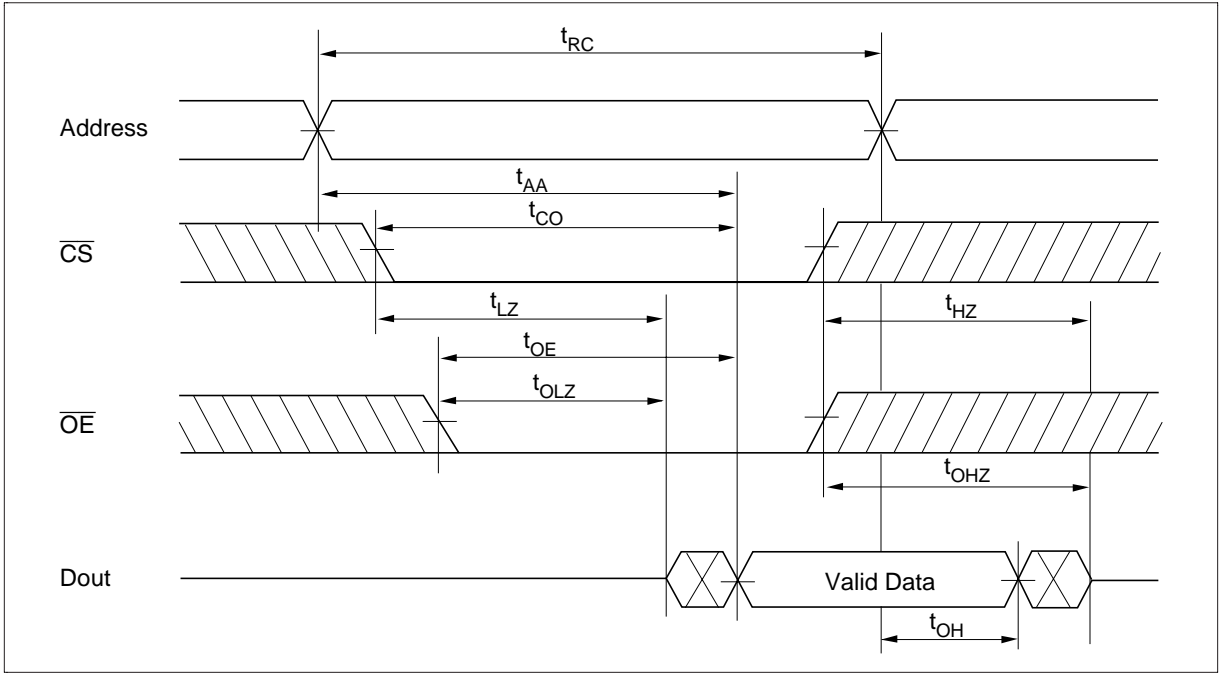
10. Dout is the read data of next address.

11. If \overline{CS} is low during this period, I/O pins are in the output state. Therefore, the input signals of the opposite phase to the outputs must not be applied to them.

12. In the write cycle with \overline{OE} low fixed, t_{WP} must satisfy the following equation to avoid a problem of data bus contention. $t_{WP} \geq t_{DW} \text{ min} + t_{WHZ} \text{ max}$

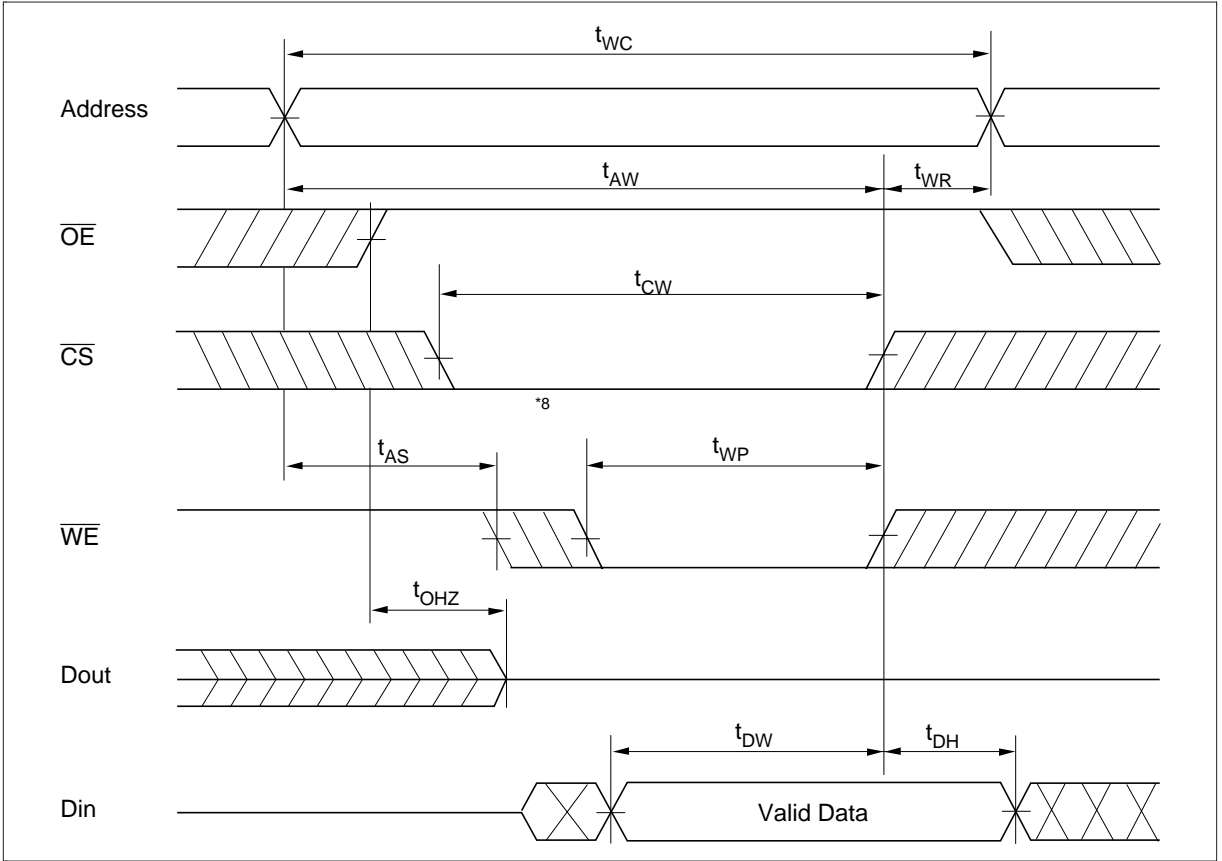
Timing Waveforms

Read Timing Waveform ($\overline{WE} = V_{IH}$)

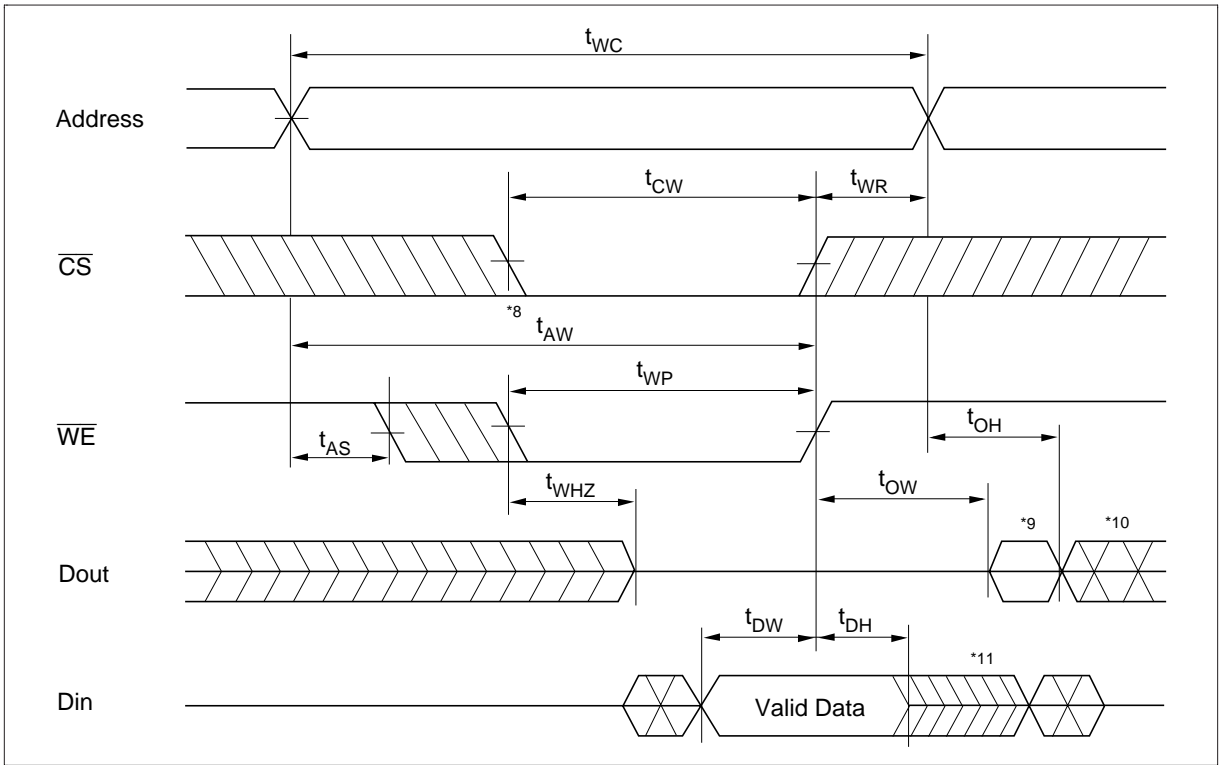


HM628512C Series

Write Timing Waveform (1) (\overline{OE} Clock)



Write Timing Waveform (2) (\overline{OE} Low Fixed)



Low V_{CC} Data Retention Characteristics ($T_a = -20$ to $+70^\circ\text{C}$)

Parameter	Symbol	Min	Typ	Max	Unit	Test conditions*3
V_{CC} for data retention	V_{DR}	2	—	—	V	$\overline{CS} \geq V_{CC} - 0.2 \text{ V}$, $V_{in} \geq 0 \text{ V}$
Data retention current	I_{CCDR}	—	0.8^{*4}	20^{*1}	μA	$V_{CC} = 3.0 \text{ V}$, $V_{in} \geq 0 \text{ V}$ $\overline{CS} \geq V_{CC} - 0.2 \text{ V}$
		—	0.8^{*4}	10^{*2}	μA	
Chip deselect to data retention time	t_{CDR}	0	—	—	ns	See retention waveform
Operation recovery time	t_R	t_{RC}^{*5}	—	—	ns	

Notes: 1. For L-version and $10 \mu\text{A}$ (max.) at $T_a = -20$ to $+40^\circ\text{C}$.

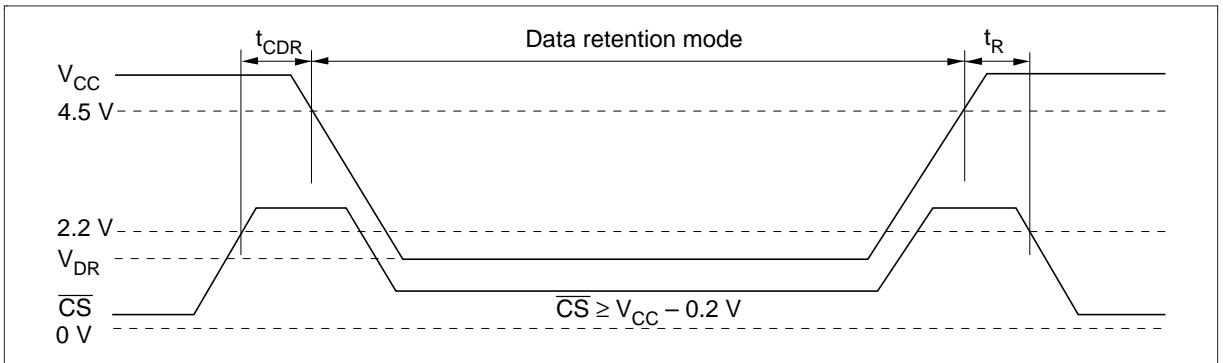
2. For L-SL-version and $3 \mu\text{A}$ (max.) at $T_a = -20$ to $+40^\circ\text{C}$.

3. \overline{CS} controls address buffer, \overline{WE} buffer, \overline{OE} buffer, and D_{in} buffer. In data retention mode, V_{in} levels (address, \overline{WE} , \overline{OE} , I/O) can be in the high impedance state.

4. Typical values are at $V_{CC} = 3.0 \text{ V}$, $T_a = +25^\circ\text{C}$ and specified loading, and not guaranteed.

5. t_{RC} = read cycle time.

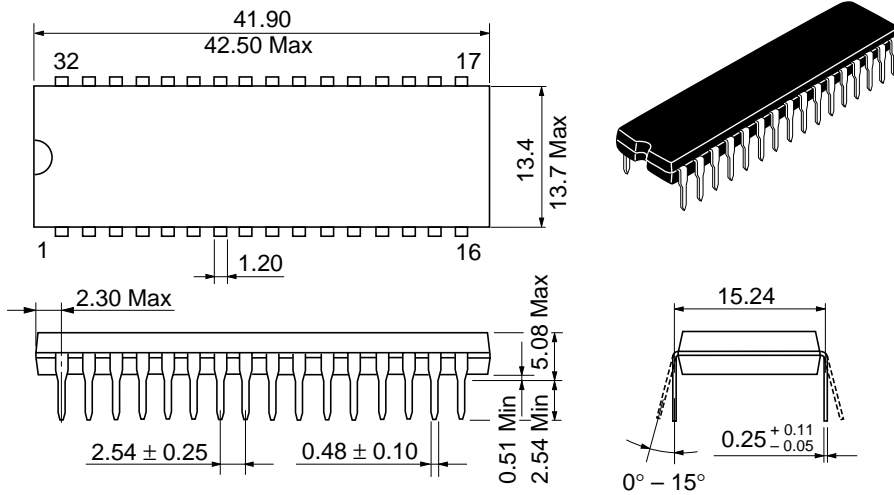
Low V_{CC} Data Retention Timing Waveform (\overline{CS} Controlled)



Package Dimensions

HM628512CLP Series (DP-32)

Unit: mm



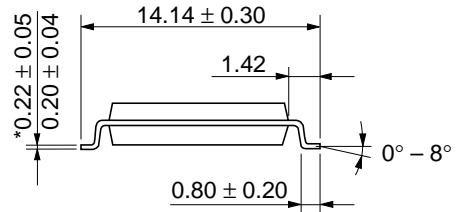
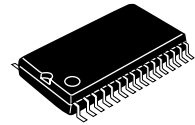
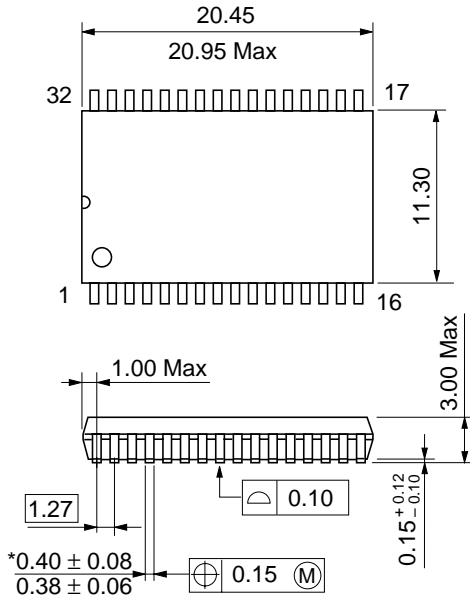
Hitachi Code	DP-32
JEDEC	—
EIAJ	Conforms
Mass (reference value)	5.1 g

HM628512C Series

Package Dimensions (cont.)

HM628512CLFP Series (FP-32D)

Unit: mm



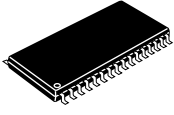
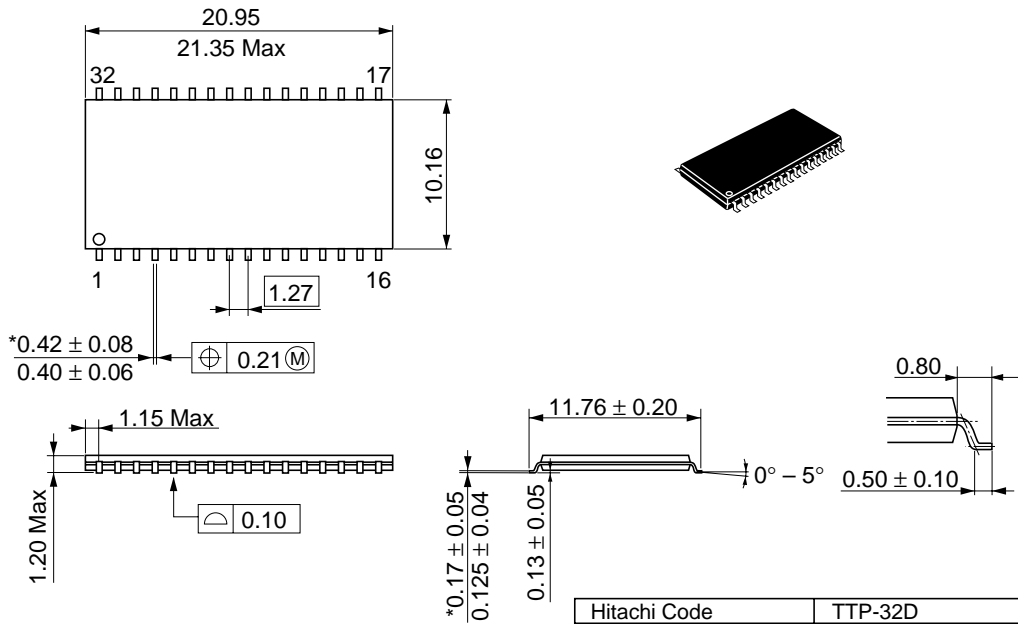
*Dimension including the plating thickness
Base material dimension

Hitachi Code	FP-32D
JEDEC	Conforms
EIAJ	—
Mass (reference value)	1.3 g

Package Dimensions (cont.)

HM628512CLTT Series (TTP-32D)

Unit: mm



*Dimension including the plating thickness
Base material dimension

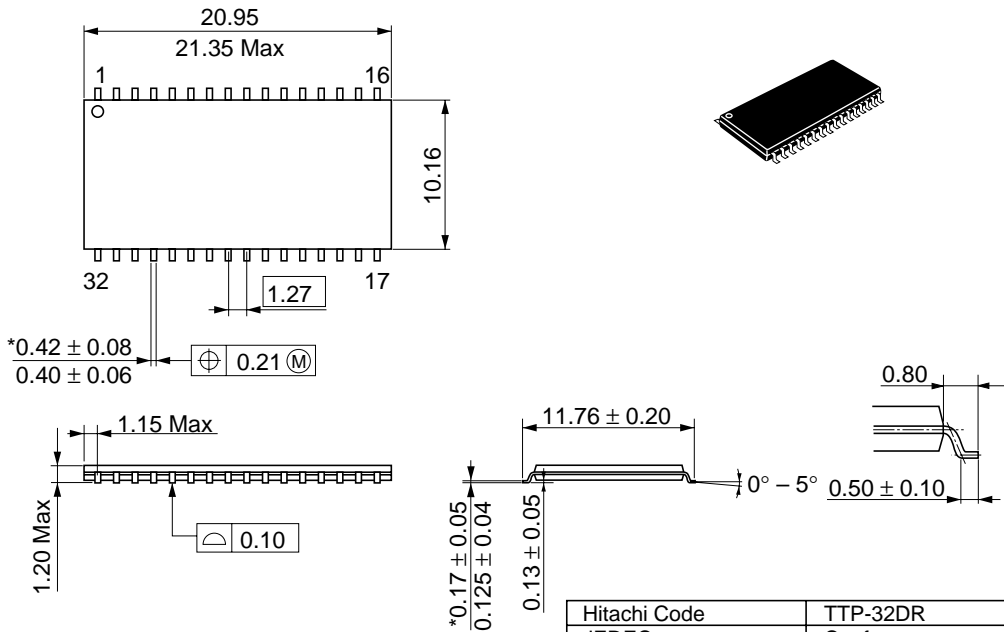
Hitachi Code	TTP-32D
JEDEC	Conforms
EIAJ	—
Mass (reference value)	0.51 g

HM628512C Series

Package Dimensions (cont.)

HM628512CLRR Series (TTP-32DR)

Unit: mm



*Dimension including the plating thickness
Base material dimension

Hitachi Code	TTP-32DR
JEDEC	Conforms
EIAJ	—
Mass (reference value)	0.51 g

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HITACHI

Hitachi, Ltd.

Semiconductor & Integrated Circuits
 Nippon Bldg., 2-6-2, Ohte-machi, Chiyoda-ku, Tokyo 100-0004, Japan
 Tel: (03) 3270-2111 Fax: (03) 3270-5109

URL NorthAmerica : <http://semiconductor.hitachi.com/>
 Europe : <http://www.hitachi-eu.com/hel/ecg>
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For further information write to:

Hitachi Semiconductor (America) Inc.
 179 East Tasman Drive
 San Jose, CA 95134
 Tel: <1>(408) 433-1990
 Fax: <1>(408) 433-0223

Hitachi Europe Ltd.
 Electronic Components Group
 Whitebrook Park
 Lower Cookham Road
 Maidenhead
 Berkshire SL6 8YA, United Kingdom
 Tel: <44> (1628) 585000
 Fax: <44> (1628) 585200

Hitachi Europe GmbH
 Electronic Components Group
 Domacher Straße 3
 D-85622 Feldkirchen, Munich
 Germany
 Tel: <49> (89) 9 9180-0
 Fax: <49> (89) 9 29 30 00

Hitachi Asia Ltd.
 Hitachi Tower
 16 Collyer Quay #20-00
 Singapore 049318
 Tel : <65>-538-6533/538-8577
 Fax : <65>-538-6933/538-3877
 URL : <http://www.hitachi.com.sg>

Hitachi Asia Ltd.
 (Taipei Branch Office)
 4/F, No. 167, Tun Hwa North Road
 Hung-Kuo Building
 Taipei (105), Taiwan
 Tel : <886>-(2)-2718-3666
 Fax : <886>-(2)-2718-8180
 Telex : 23222 HAS-TP
 URL : <http://www.hitachi.com.tw>

Hitachi Asia (Hong Kong) Ltd.
 Group III (Electronic Components)
 7/F., North Tower
 World Finance Centre,
 Harbour City, Canton Road
 Tsim Sha Tsui, Kowloon
 Hong Kong
 Tel : <852>-(2)-735-9218
 Fax : <852>-(2)-730-0281
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